

FGHL40S65UQ

Product Preview

Field Stop Trench IGBT 40 A, 650 V

Using the novel field stop generation IGBT technology, ON Semiconductor's new series of field stop 4th generation of RC IGBTs offer superior conduction and switching performance and easy parallel operation. This device is well suited for the resonant or soft switching application such as induction heating and microwave oven.

Features

- Maximum Junction Temperature: $T_J = 175^\circ\text{C}$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage: $V_{CE(sat)} = 1.36\text{ V (Typ.)}$ @ $I_C = 40\text{ A}$
- 100% of the Parts tested for I_{LM} (Note 1)
- High Input Impedance
- Fast Switching
- Tighten Parameter Distribution
- RoHS Compliant
- IGBT with Monolithic Reverse Conducting Diode

Typical Applications

- Induction Heating
- Microwave Oven
- Soft Switching Application

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector to Emitter Voltage	V_{CES}	650	V
Gate to Emitter Voltage	V_{GES}	± 20	V
Transient Gate to Emitter Voltage		± 30	
Collector Current @ $T_C = 25^\circ\text{C}$	I_C	80	A
@ $T_C = 100^\circ\text{C}$		40	
Pulsed Collector Current (Note 1)	I_{LM}	120	A
Pulsed Collector Current (Note 2)	I_{CM}	120	A
Diode Forward Current @ $T_C = 25^\circ\text{C}$	I_F	40	A
@ $T_C = 100^\circ\text{C}$		20	
Pulsed Diode Maximum Forward Current	I_{FM}	120	A
Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$	P_D	231	W
@ $T_C = 100^\circ\text{C}$		115	
Operating Junction / Storage Temperature Range	T_J, T_{STG}	-55 to +175	$^\circ\text{C}$
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	T_L	260	$^\circ\text{C}$

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

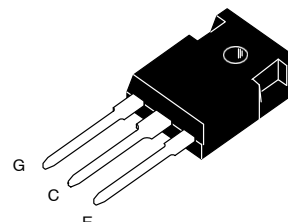
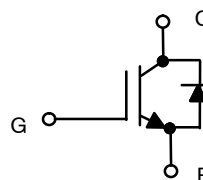
1. $V_{CC} = 400\text{ V}$, $V_{GE} = 15\text{ V}$, $I_C = 120\text{ A}$, $R_G = 7\ \Omega$, Inductive Load, 100% Tested.
2. Repetitive rating: pulse width limited by max. Junction temperature.



ON Semiconductor®

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40 A, 650 V
 $V_{CE(sat)} = 1.36\text{ V (Typ.)}$



TO-247-3L
CASE 340CX

MARKING DIAGRAM



&Y = ON Semiconductor Logo
&Z = Assembly Plant Code
&3 = 3-Digit Data Code
&K = 2-Digit Lot Traceability Code
FGHL40S65UQ = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping
FGHL40S65UQ	TO-247-3L	30 Units / Rail

This document contains information on a product under development. ON Semiconductor reserves the right to change or discontinue this product without notice.

FGHL40S65UQ

THEMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{\theta JC}$	0.65	$^{\circ}\text{C}/\text{W}$
Thermal resistance junction-to-case, for Diode	$R_{\theta JC}$	1.69	$^{\circ}\text{C}/\text{W}$
Thermal resistance junction-to-ambient	$R_{\theta JA}$	40	$^{\circ}\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}\text{C}$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
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OFF CHARACTERISTIC

Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0\text{ V}, I_C = 1\text{ mA}$	BV_{CES}	650	–	–	V
Temperature Coefficient of Breakdown Voltage	$V_{GE} = 0\text{ V}, I_C = 1\text{ mA}$	$\Delta BV_{CES}/\Delta T_J$	–	0.5	–	$\text{V}/^{\circ}\text{C}$
Collector-emitter cut-off current, gate-emitter short-circuited	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}$	I_{CES}	–	–	250	μA
Gate leakage current, collector-emitter short-circuited	$V_{GE} = 20\text{ V}, V_{CE} = 0\text{ V}$	I_{GES}	–	–	± 400	nA

ON CHARACTERISTIC

Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_C = 40\text{ mA}$	$V_{GE(th)}$	2.5	4.7	6.5	V
Collector-emitter saturation voltage	$V_{GE} = 15\text{ V}, I_C = 40\text{ A}$ $V_{GE} = 15\text{ V}, I_C = 40\text{ A}, T_J = 175^{\circ}\text{C}$	$V_{CE(sat)}$	–	1.36 1.6	1.7 –	V

DYNAMIC CHARACTERISTIC

Input capacitance	$V_{CE} = 30\text{ V}, V_{GE} = 0\text{ V}, f = 1\text{ MHz}$	C_{ies}	–	6054	–	pF
Output capacitance		C_{oes}	–	36	–	
Reverse transfer capacitance		C_{res}	–	30	–	
Gate charge total	$V_{CE} = 400\text{ V}, I_C = 40\text{ A},$ $V_{GE} = 15\text{ V}$	Q_g	–	306	–	nC
Gate to emitter charge		Q_{ge}	–	30	–	
Gate to collector charge		Q_{gc}	–	99	–	

SWITCHING CHARACTERISTIC, INDUCTIVE LOAD

Turn-on delay time	$T_J = 25^{\circ}\text{C}$ $V_{CC} = 400\text{ V}, I_C = 40\text{ A},$ $R_G = 6\ \Omega$ $V_{GE} = 15\text{ V}$ Inductive Load	$t_{d(on)}$	–	32	–	ns
Rise time		t_r	–	20	–	
Turn-off delay time		$t_{d(off)}$	–	260	–	
Fall time		t_f	–	13	–	
Turn-on switching loss		E_{ON}	–	1760	–	μJ
Turn-off switching loss		E_{OFF}	–	362	–	
Total switching loss		E_{TS}	–	2122	–	
Turn-on delay time	$T_J = 175^{\circ}\text{C}$ $V_{CC} = 400\text{ V}, I_C = 40\text{ A},$ $R_G = 6\ \Omega$ $V_{GE} = 15\text{ V}$ Inductive Load	$t_{d(on)}$	–	30	–	ns
Rise time		t_r	–	28	–	
Turn-off delay time		$t_{d(off)}$	–	284	–	
Fall time		t_f	–	56	–	
Turn-on switching loss		E_{ON}	–	2050	–	μJ
Turn-off switching loss		E_{OFF}	–	590	–	
Total switching loss		E_{TS}	–	2640	–	

FGHL40S65UQ

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$ unless otherwise specified) (continued)

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
DIODE CHARACTERISTIC						
Forward voltage	$I_F = 20\text{ A}$ $I_F = 20\text{ A}, T_J = 175^\circ\text{C}$	V_F	– –	1.24 1.24	1.6 –	V
Reverse Recovery Energy	$I_F = 20\text{ A}, \Delta I_F/\Delta t = 200\text{ A}/\mu\text{s}$	E_{REC}	–	359	–	μJ
Diode Reverse Recovery Time	$I_F = 20\text{ A}, \Delta I_F/\Delta t = 200\text{ A}/\mu\text{s}$ $I_F = 20\text{ A}, \Delta I_F/\Delta t = 200\text{ A}/\mu\text{s},$ $T_J = 175^\circ\text{C}$	T_{RR}	–	319 430	–	nS
Diode Reverse Recovery Charge	$I_F = 20\text{ A}, \Delta I_F/\Delta t = 200\text{ A}/\mu\text{s}$ $I_F = 20\text{ A}, \Delta I_F/\Delta t = 200\text{ A}/\mu\text{s},$ $T_J = 175^\circ\text{C}$	Q_{RR}	–	1853 3007	–	nC

FGHL40S65UQ

TYPICAL CHARACTERISTICS

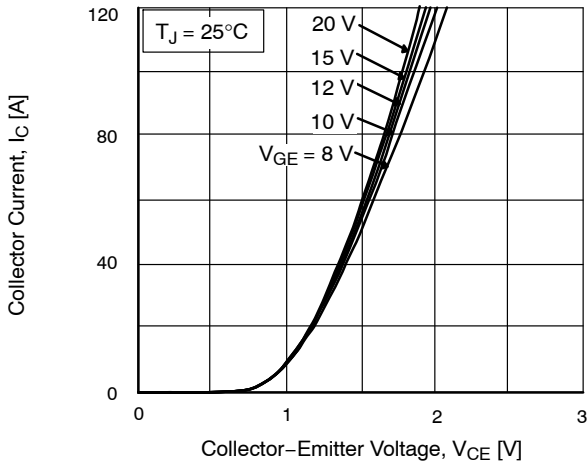


Figure 1. Typical Output Characteristics

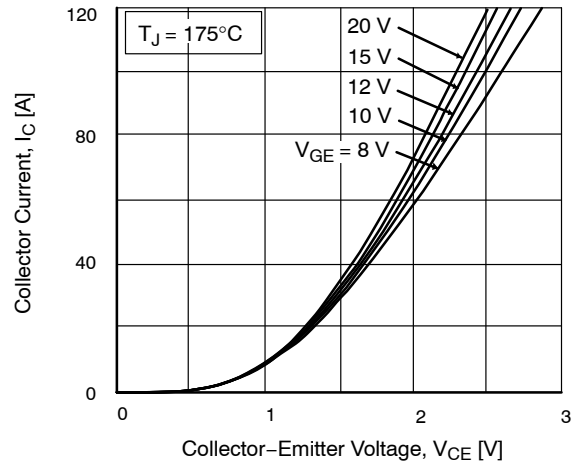


Figure 2. Typical Output Characteristics

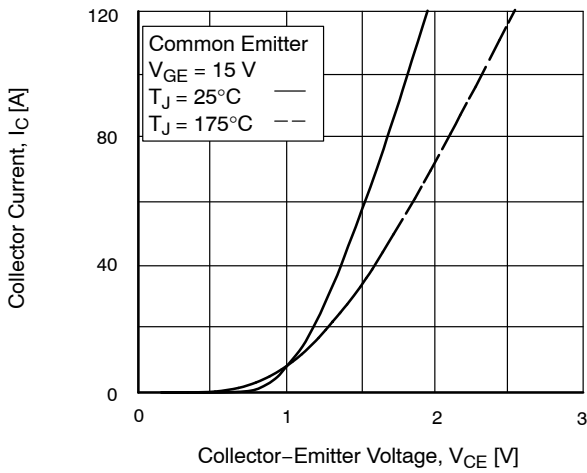


Figure 3. Typical Saturation Voltage Characteristics

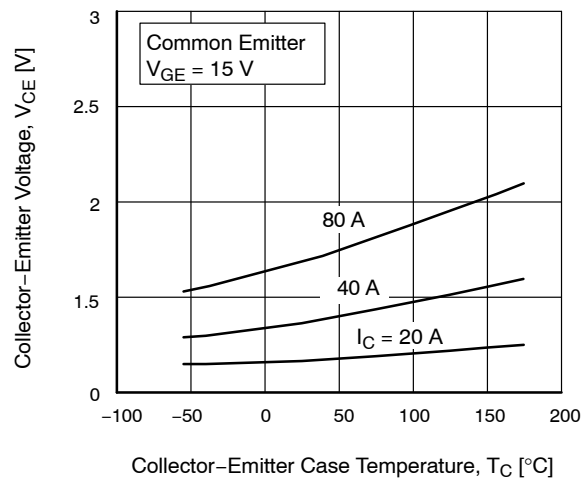


Figure 4. Saturation Voltage vs. Case Temperature at Variant Current Level

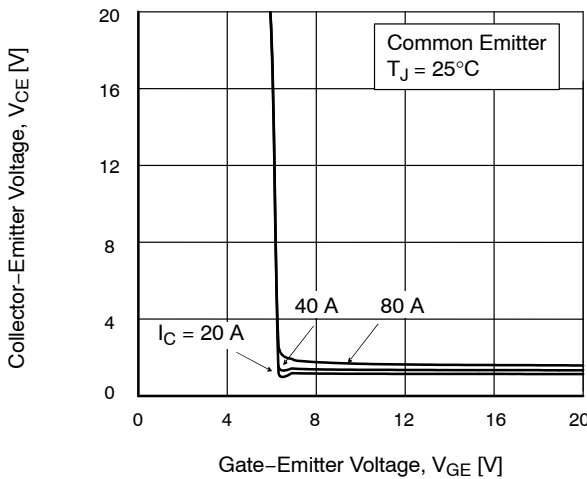


Figure 5. Saturation Voltage vs V_{GE}

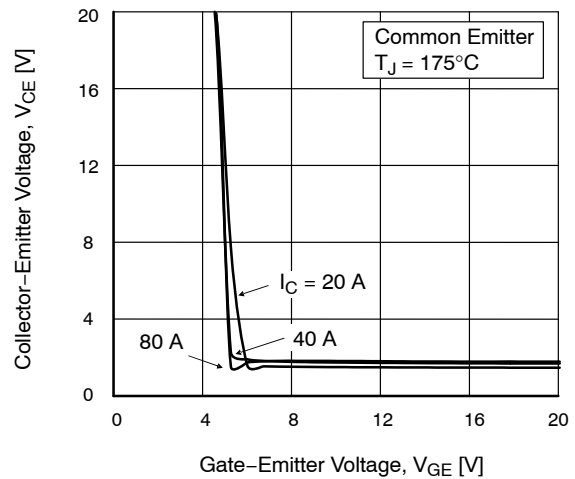


Figure 6. Saturation Voltage vs V_{GE}

FGHL40S65UQ

TYPICAL CHARACTERISTICS (continued)

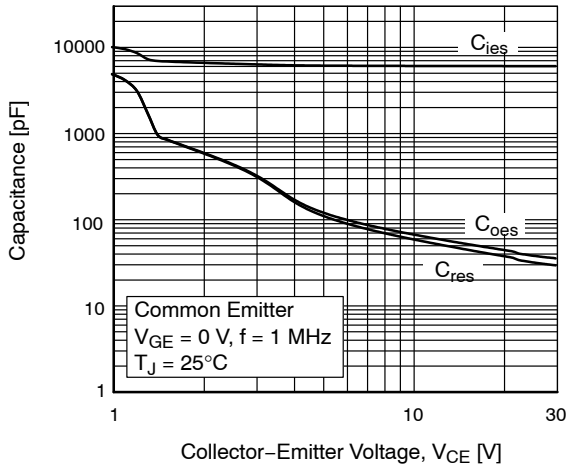


Figure 7. Capacitance Characteristics

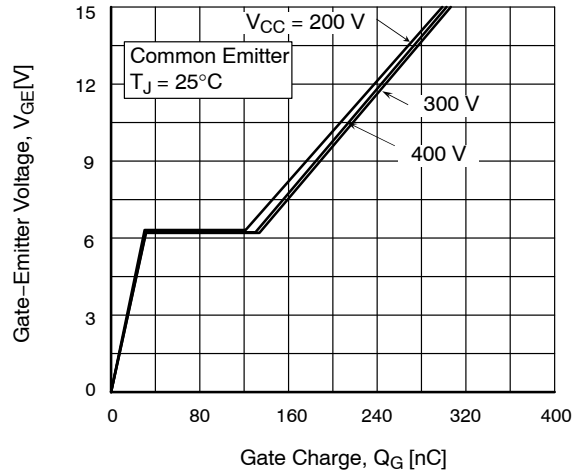


Figure 8. Gate Charge Characteristics

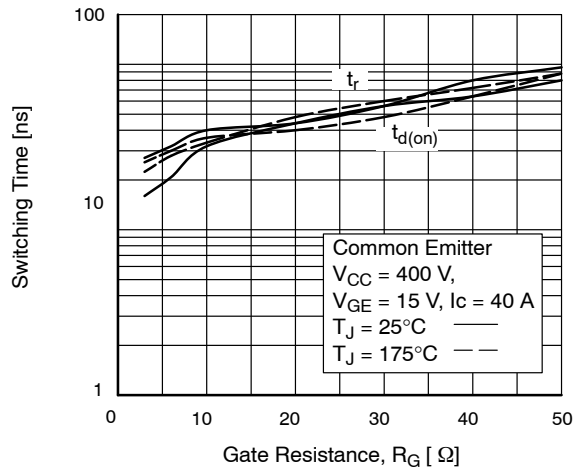


Figure 9. Turn-on Characteristics vs. Gate Resistance

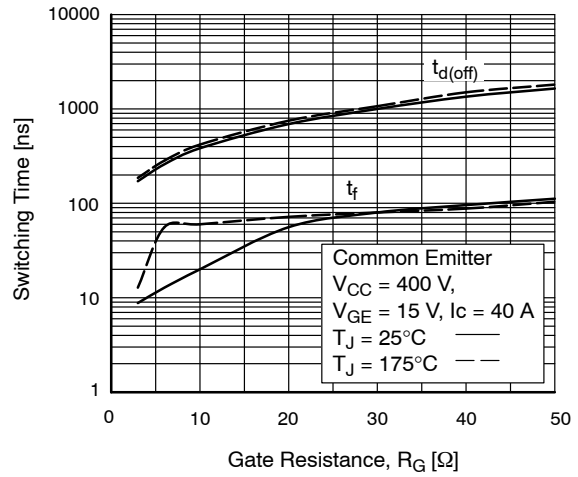


Figure 10. Turn-off Characteristics vs. Gate Resistance

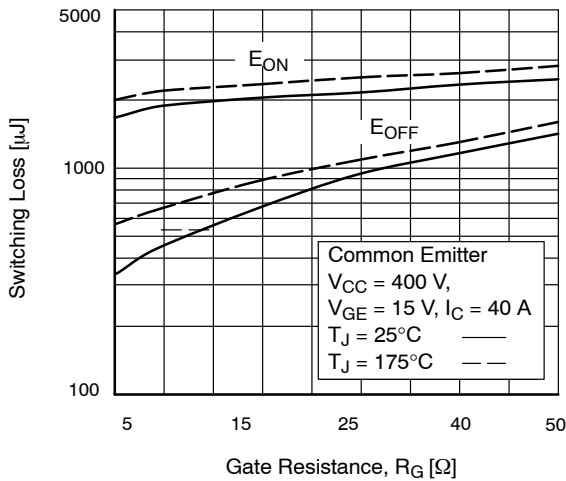


Figure 11. Switching Loss vs Gate Resistance

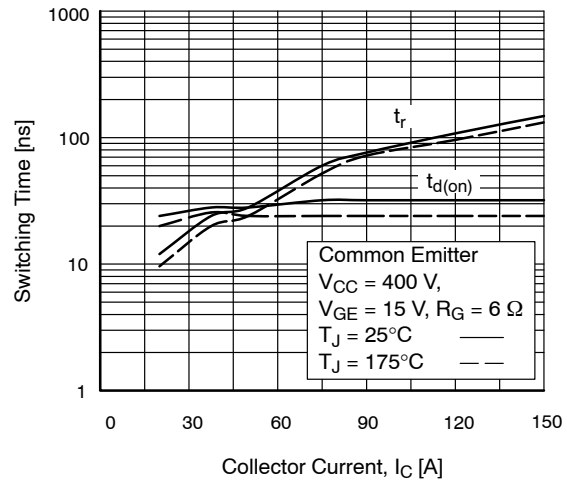


Figure 12. Turn-on Characteristics vs. Collector Current

FGHL40S65UQ

TYPICAL CHARACTERISTICS (continued)

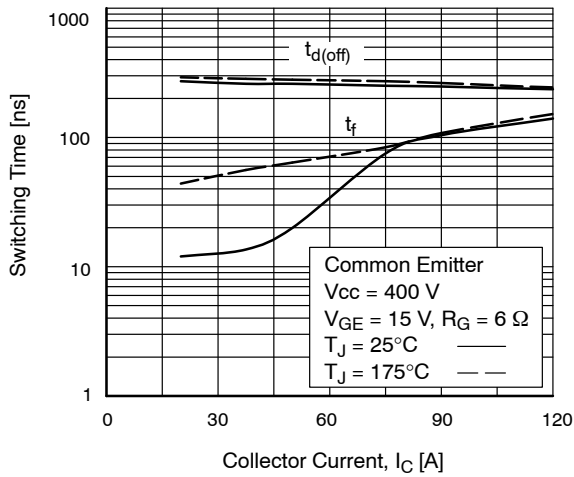


Figure 13. Turn-Off Characteristics vs. Collector Current

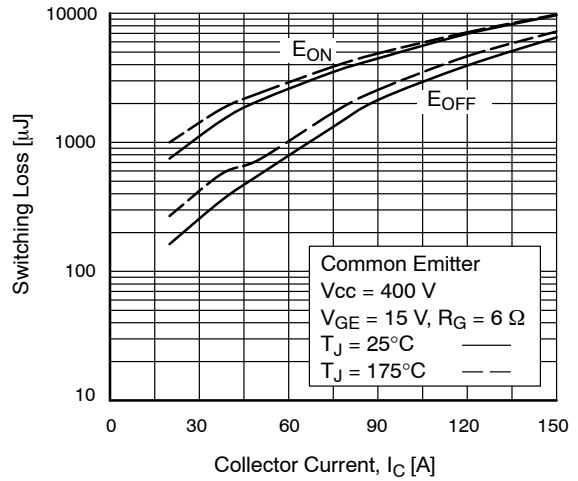


Figure 14. Switching Loss vs. Collector Current

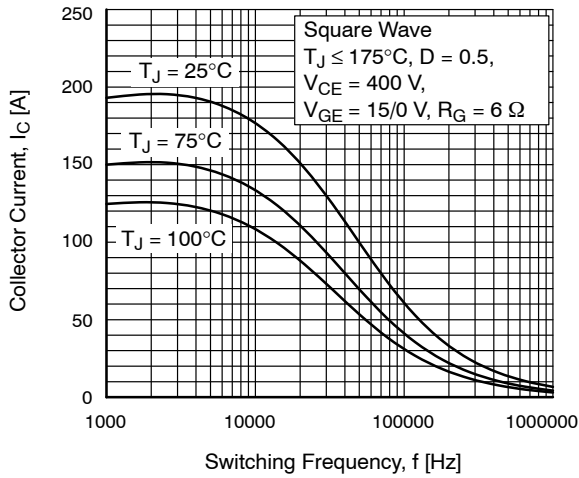


Figure 15. Load Current vs. Frequency

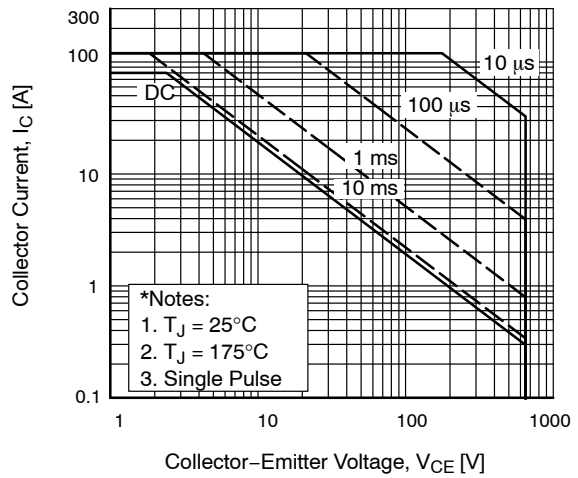


Figure 16. SOA Characteristics (FBSOA)

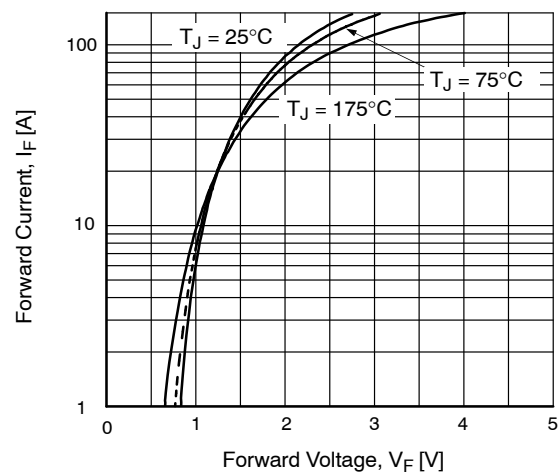


Figure 17. Forward Characteristics

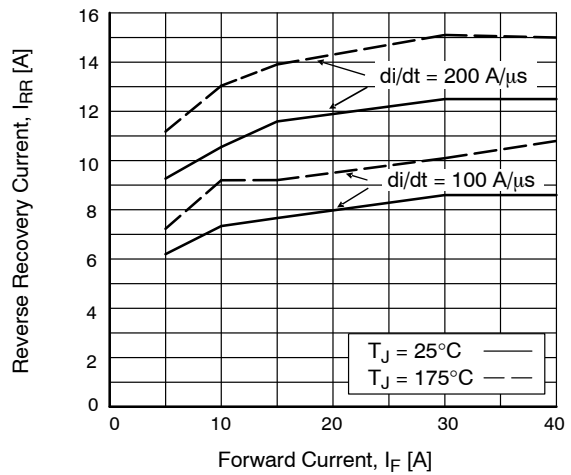


Figure 18. Reverse Recovery Current

FGHL40S65UQ

TYPICAL CHARACTERISTICS (continued)

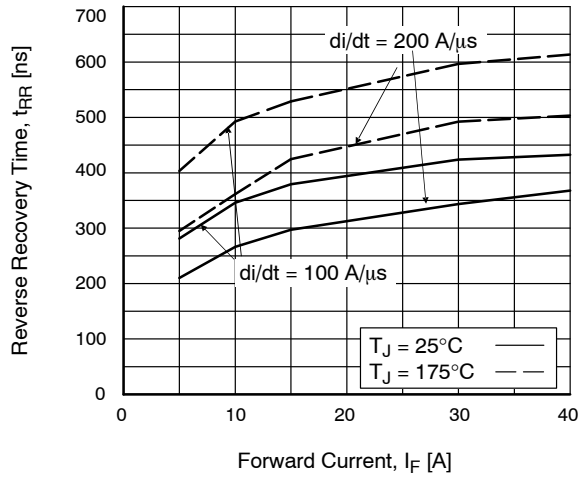


Figure 19. Reverse Recovery Time

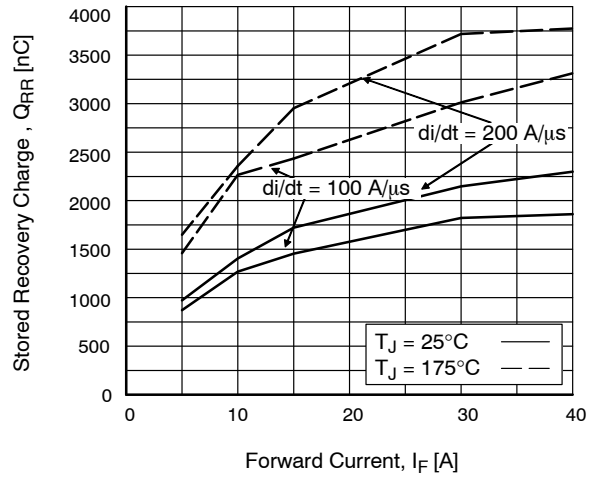


Figure 20. Stored Charge

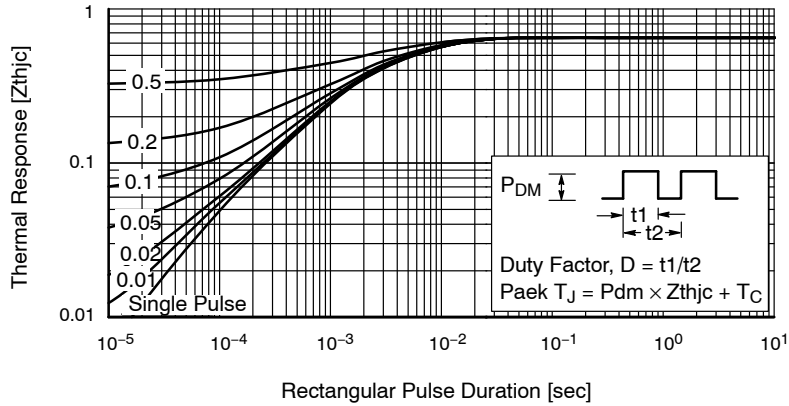


Figure 21. Transient Thermal Impedance of IGBT

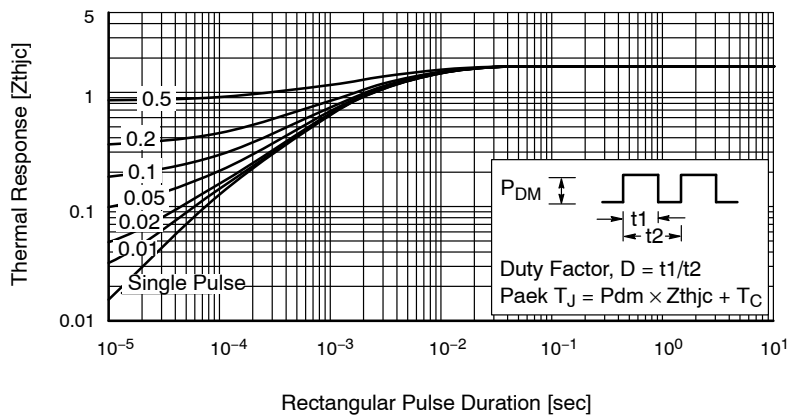
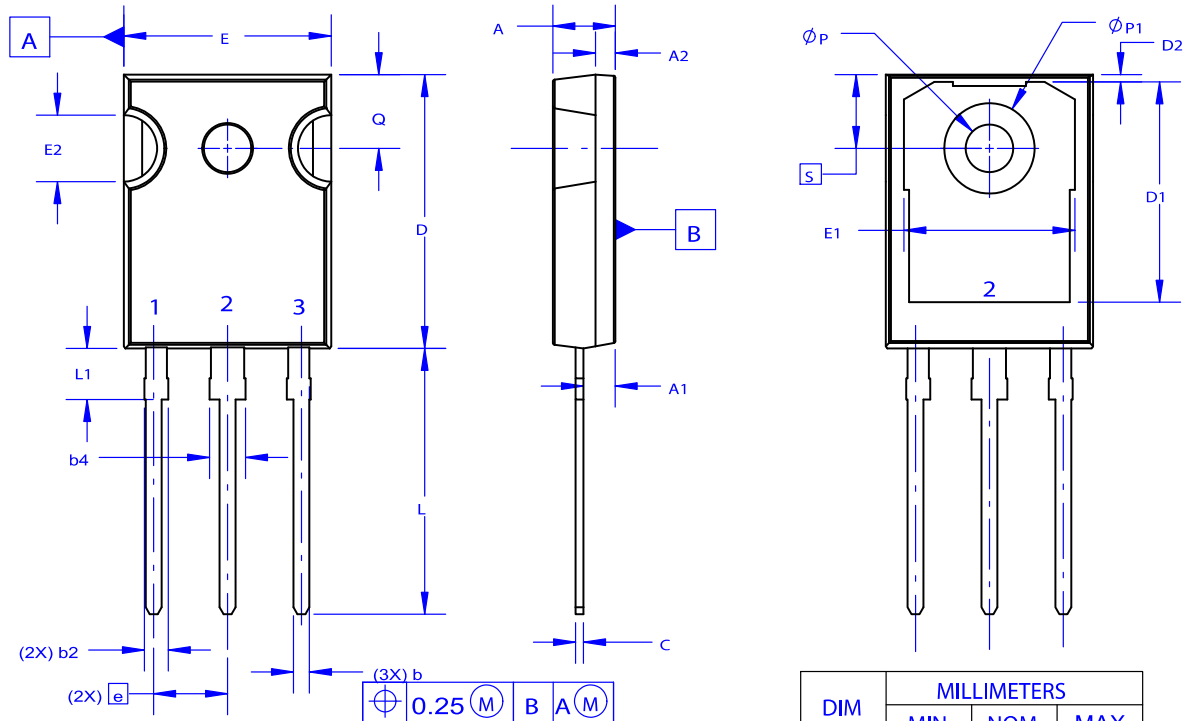


Figure 22. Transient Thermal Impedance of Diode

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TO-247-3LD
CASE 340CX
ISSUE O



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 - 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

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